



QUAD development

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NIKHEF

Nikhef/Bonn LepCol meeting
September 25, 2017

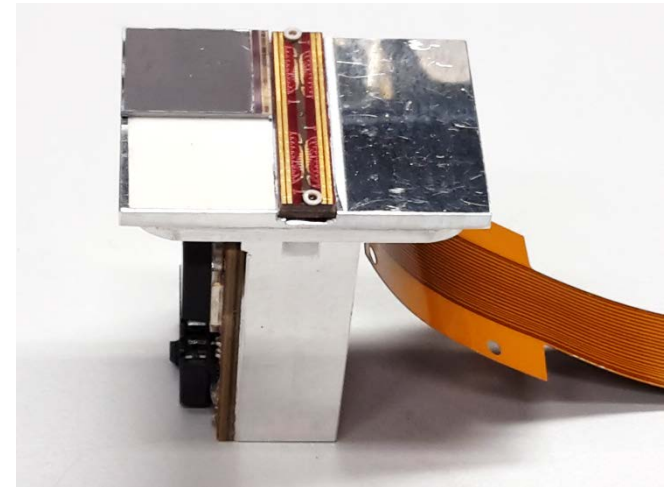
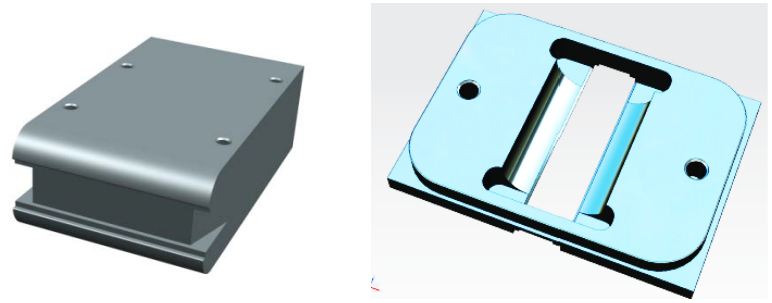
First electrical QUAD (QUAD 1)

- QUAD 1 being tested
 - Chips show sign of life
 - But DAQ configuration still going on by Bas
- Error found
 - 3 bonds to a termination pin have to be rerouted from VCC to GND
- We need confirmation of proper functioning before ordering a second batch (~15k €)



QUAD 2

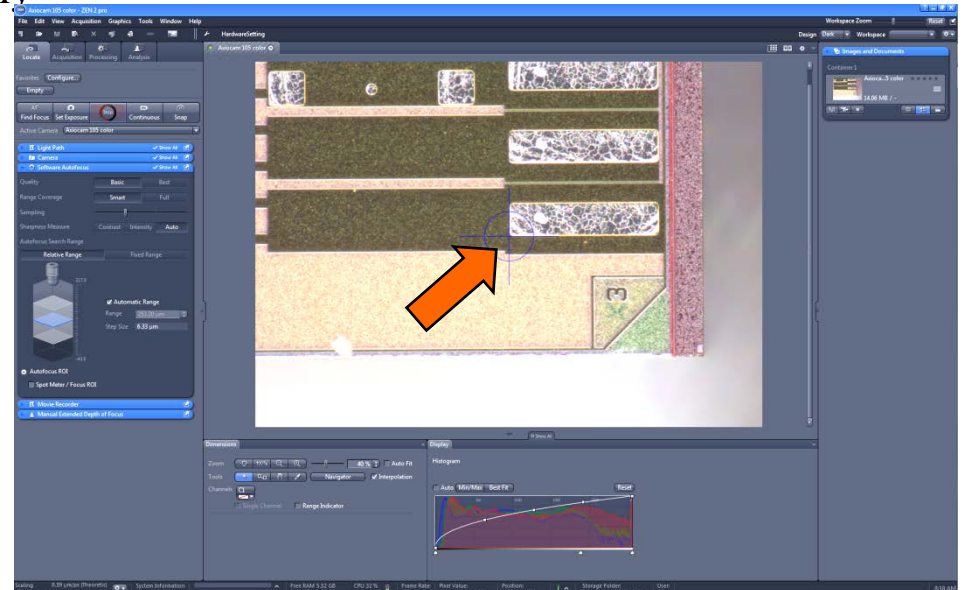
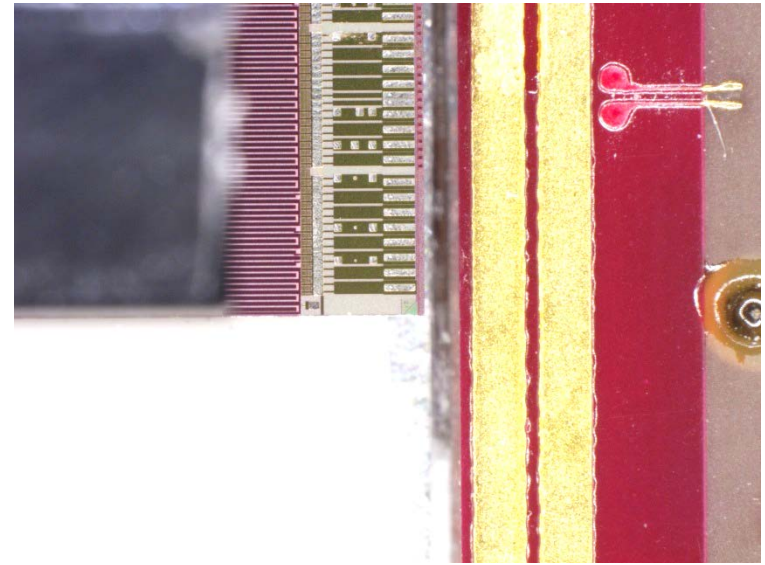
- Coca and stump fabricated to latest modifications
- QUAD 2 glued together using jig
 - Still stump few degrees off
- We have bought surgical microscope to avoid damage when machining wirebond PCB
- Coca surface well cleaned
- Positioning tests with class E chip
 - Wrinkled grid
- Chip is first aligned at $\sim 300 \mu\text{m}$ above the thermal tape
- Only minor error in XY position after pushing the chip onto the tape
 - Chip does not move anymore when touching it
- Whole alignment procedure is going smoothly now



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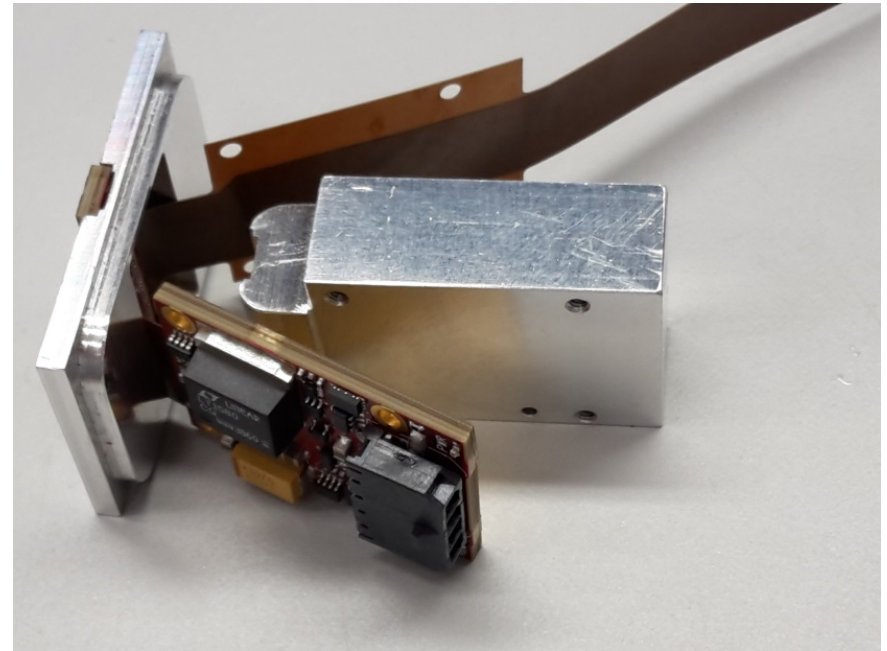
Chip position in XY

- Preliminary verified
 - 1st bonding pad: $\Delta X = 3.6 \mu\text{m}$, $\Delta Y = 1.4 \mu\text{m}$
 - 2nd bonding pad: $\Delta X = 2.9 \mu\text{m}$, $\Delta Y = 8.0 \mu\text{m}??$
- Dedicated metrology program in progress
- Fine tuning of the chip XY position parameters
 - Nominal distance of chip edge to coca edge: $13 \mu\text{m}$
 - Hard to detect precisely the edge of the coca
 - Edge looks quite rough under the microscope
- Chips held very tight by the thermal tape
 - First chip broke when trying to remove it
 - But using some alcohol it went smoothly



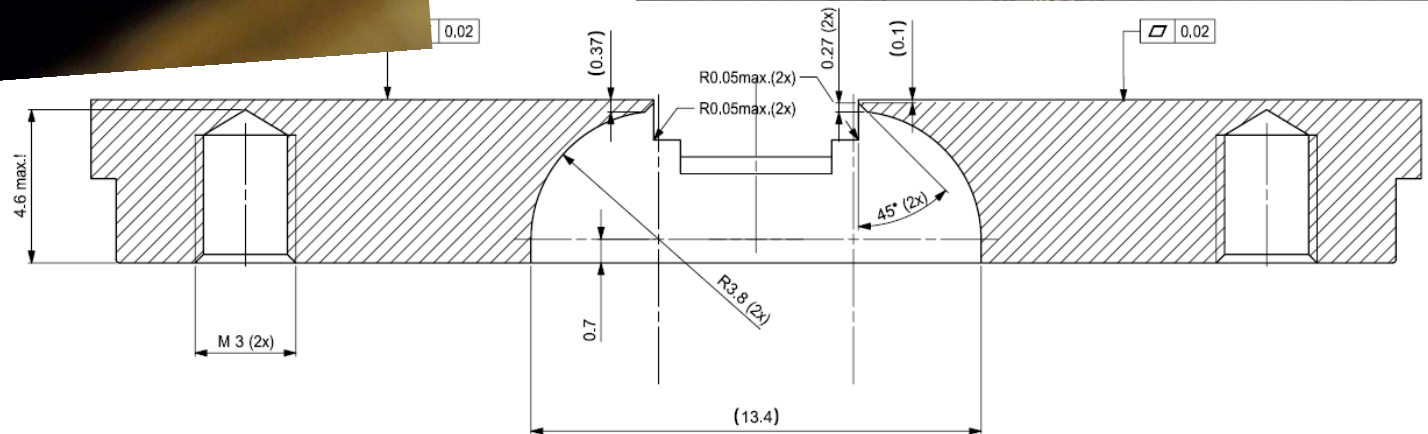
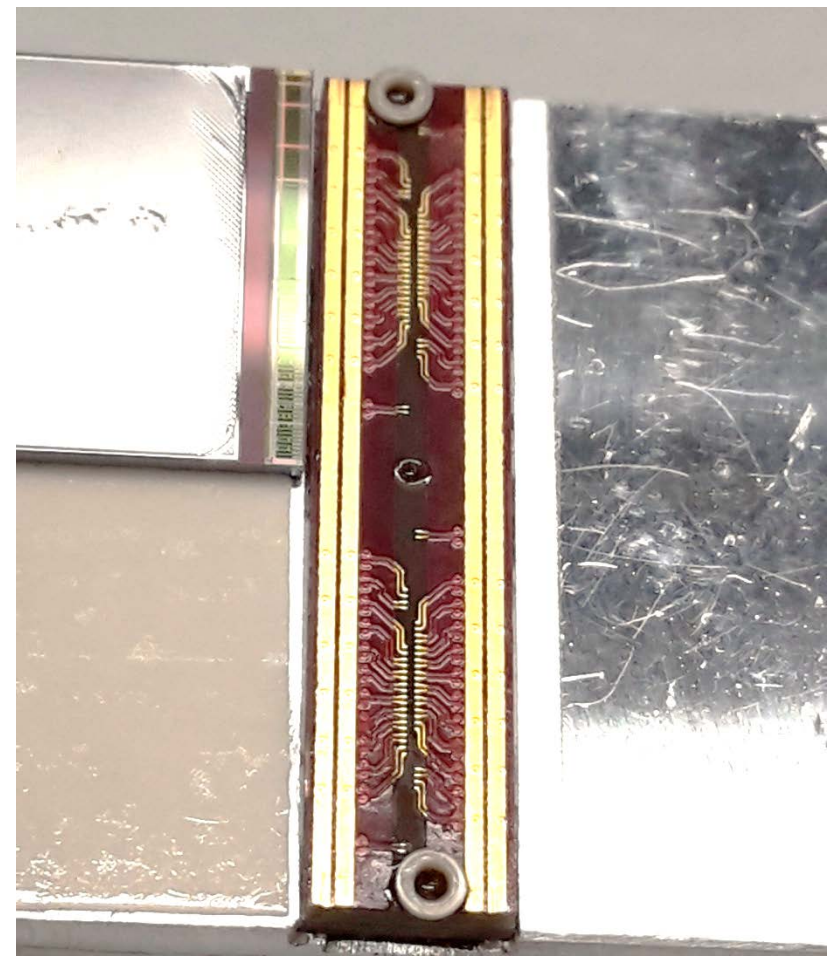
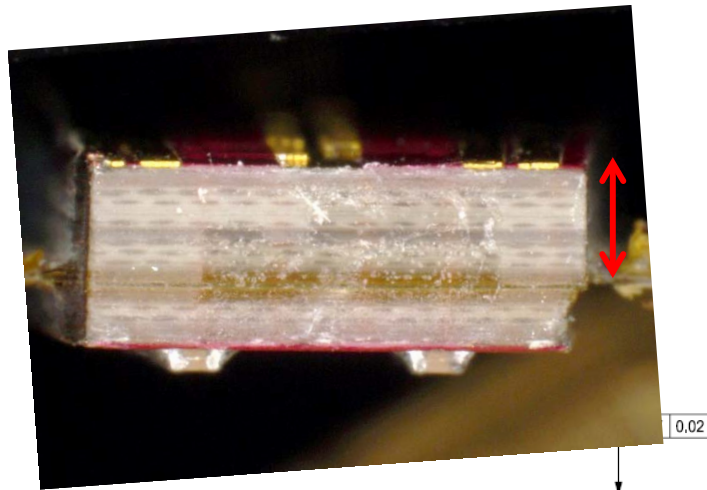
Chip position in Z

- We use as reference the underside of the coca
 - Coca thickness (4.8 mm) quite well
 - +/- 20 μm
- Z of chip was preliminary verified
 - Within specs along the bonding pads
 - But 30 μm higher at the opposite side
 - Coca does likewise
 - Both coca halves only weakly connected
 - May be pushed upwards by the flexes
 - Could be improved when mounted on support plate



Bending wirebond PCB

- The wirebond PCB is bend downwards with 100 μm sagitta
 - Only supported at both ends
 - Pushed down in the middle by the flex
- Next PCB design we have to increase the distance between PCB surface and flex
 - Now: 1.2 – 1.3 mm

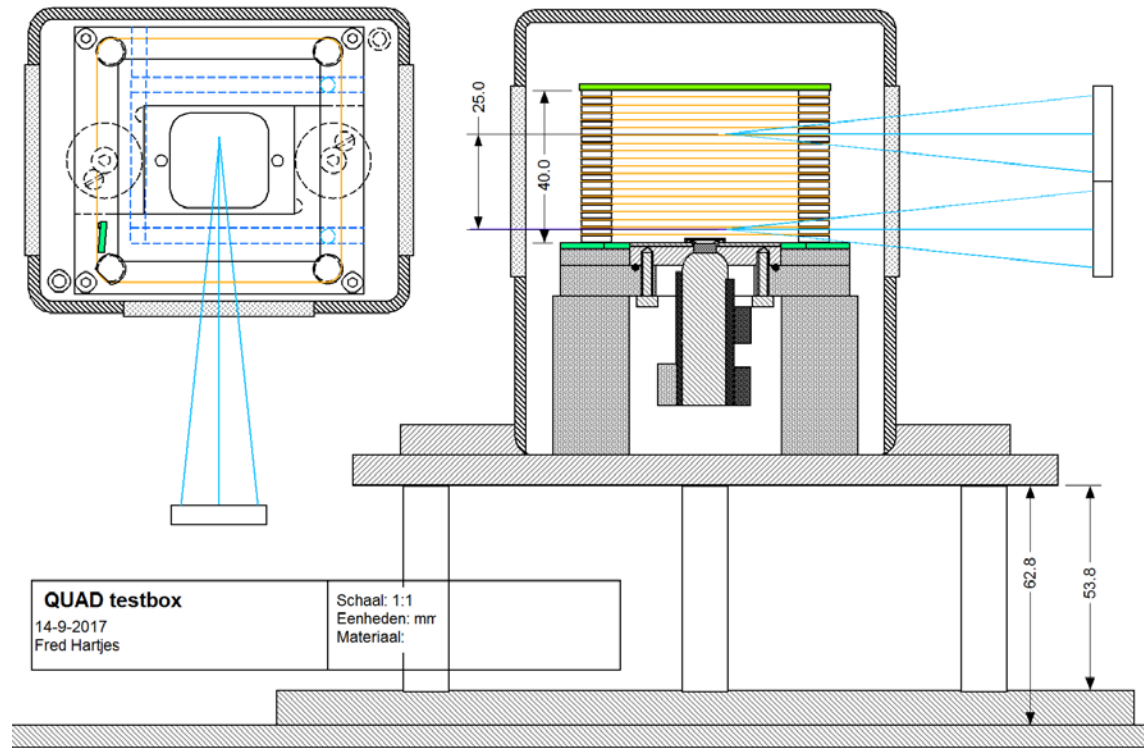
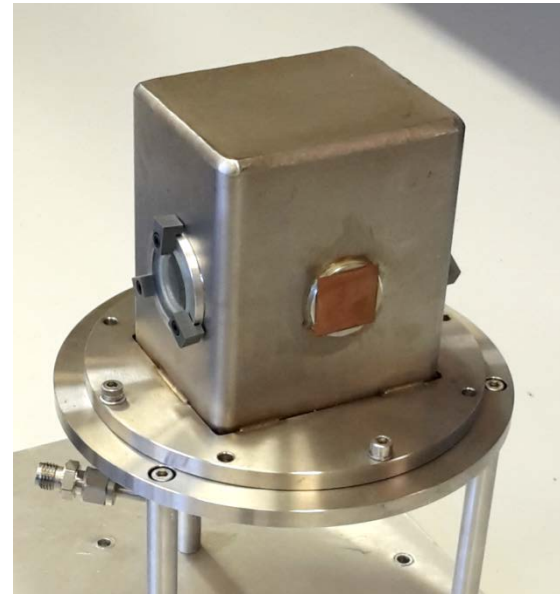


Finishing electrical QUAD 2

- According to Jochen's mail we will get this week 18 chips:
 - 9 D
 - 3 C
 - 2 B
 - 4 A
- Since we still have components to populate 2 electrical QUADs my suggestion is to use for QUAD 2 and QUAD 3:
 - 2 A
 - 1 B
 - 1 C
- This leaves us for spare in case of failure
 - 9 D
 - 1 C
- In principle I could finish QUAD 2 within 1 week
 - But as a safety we might wait until Bas can communicate with QUAD 1
 - We do not need QUAD 2 earlier than after finishing the testbox i.e around October 6

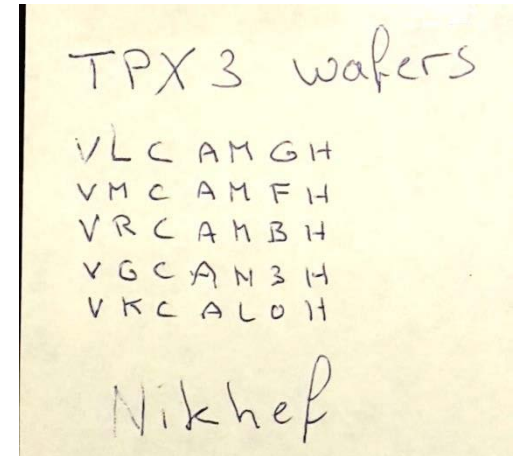
Testbox for single QUAD

- Intended for UV laser measurements
- Components in production
 - Expected this week
 - Assembly ~ 1 week
- On laser setup two new 50 mm actuators installed
 - 50 x 50 mm in XY plane
 - Covering the full QUAD surface
 - 25 mm range in Z
 - LabVIEW control to be updated (Kevin)



TPX3 wafers at Nikhef

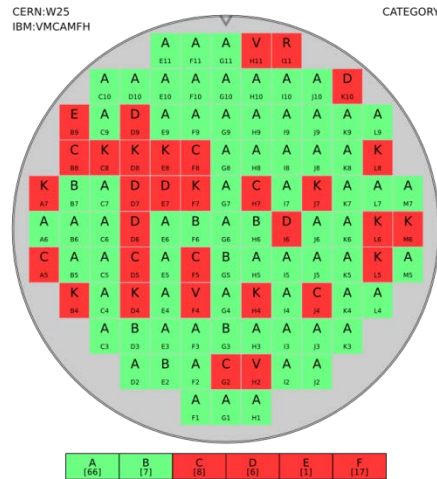
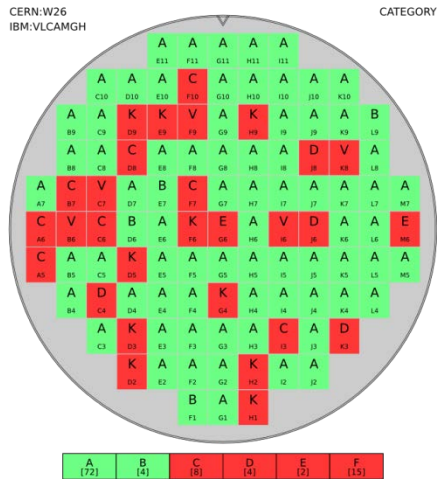
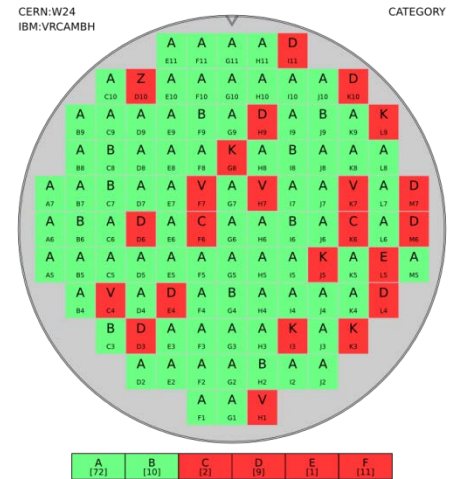
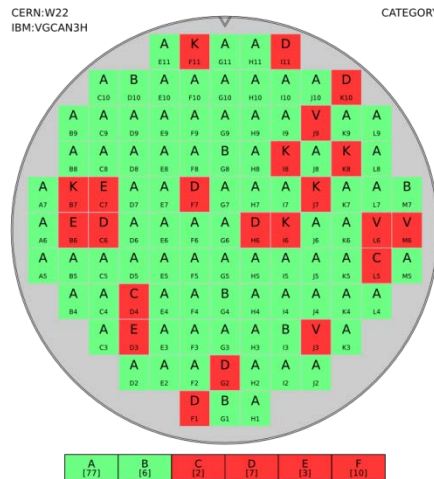
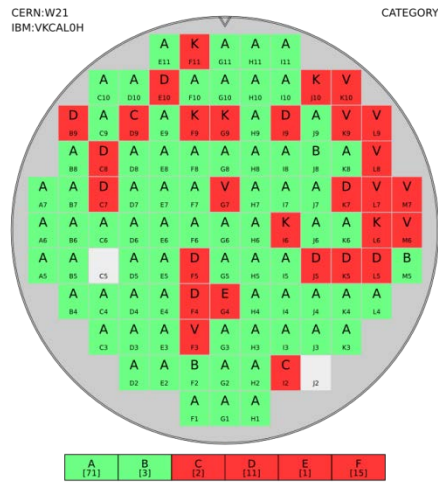
- 5/6 wafers sent to Nikhef on July 31, 2015 (Jan Visser)
- High yield wafers
 - Average 78 out of 105 good chips (A or B) per wafer (74%)
- Costs: 2620 CHF/wafer
- We have had already one low yield wafer (W16?)
- Waiting for contact with persons in charge before sending two to Yevgen



IBM number	Date Code	CERN number	Tested	When	A	B	C	D	E	F	
VTCAQQH		1528W020	Yes	23-7-2025		75	6	5	4	2	13
VKCALOH		1528W021	Yes	23-7-2025		71	3	2	11	1	15
VGCAN3H		1528W022	Yes	24-7-2015		77	6	2	7	3	10
VRCAMBH		1528W024	Yes	27-7-2016		72	10	2	9	1	11
VMCAMFH		1528W025	Yes	28-7-2015		66	7	8	6	1	17
VLCAMGH		1528W026	Yes	28-7-2015		72	4	8	4	2	15

Wafer maps

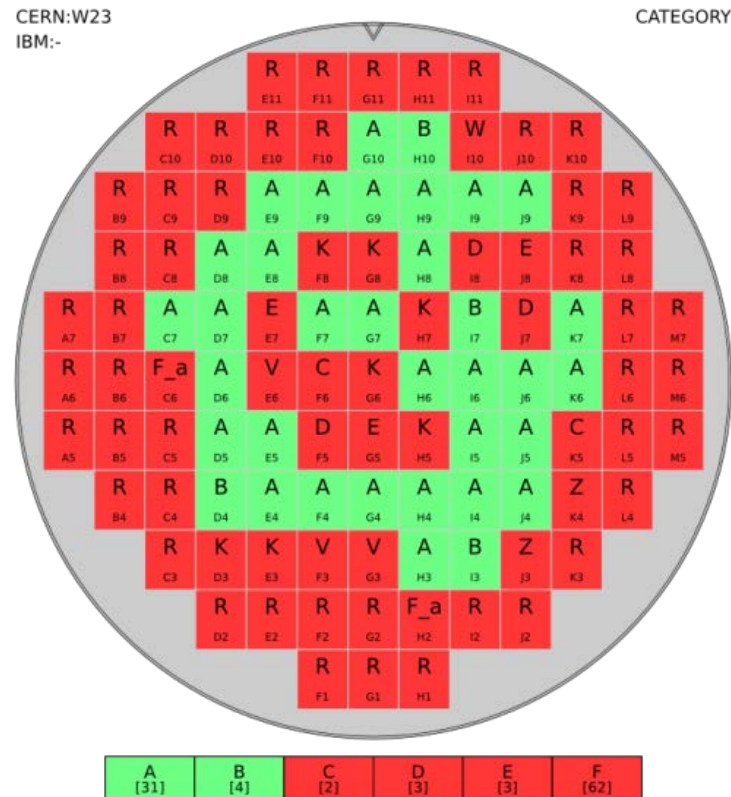
■ Made by Jerome Alozy (CERN)



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Another low yield wafer?

- Chips are mainly class A or F
- 35 good chips (class A (B))
 - 45% of high yield wafer
- Only 8 class C, E or E
- 62 class F chips (59%)



Assembly frame

- 25 x 25 mm holes
- Cooling by pipes in the frame
 - Excellent thermal contact between chips and cooling channels

